



EMI TEST REPORT

Test Report No. : 11075975H-B

Applicant : Sharp Corporation, Consumer Electronics Company,
Communication Systems Division

Type of Equipment : Cellular Phone

Model No. : SH-03H

FCC ID : APYHRO00231

Test standard : FCC Part 15 Subpart B 2015 Class B

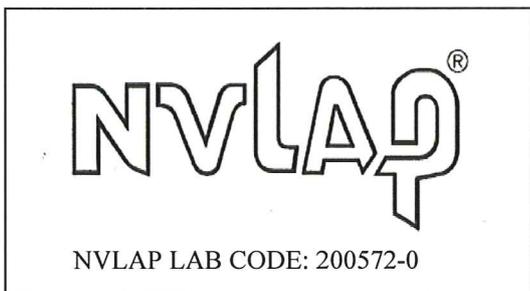
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)

Date of test: January 7, 2016

Representative test engineer: T. Shimada
Takumi Shimada
Engineer
Consumer Technology Division

Approved by : T. Hatakech
Takahiro Hatakeda
Leader
Consumer Technology Division



This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
http://japan.ul.com/resources/emc_accredited/

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SECTION 1: Customer information

Company Name : Sharp Corporation, Consumer Electronics Company, Communication Systems Division
Address : 2-13-1 Iida Hachihonmatsu Higashi Hiroshima-City, Hiroshima, 739-0192 Japan
Telephone Number : +81-82-420-1552
Facsimile Number : +81-82-420-1555
Contact Person : Hiroyuki Uwatoko

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : SH-03
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : January 6, 2016
Country of Mass-production : China
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : SH-03H is Quad-band WCDMA(FDD I / V / VI / XIX) Cellular Phone.
The EUT has the function that Bluetooth wireless technology interface.
Clock frequencies in the system : CPU: 1.200 MHz (max)
Source oscillation: 19.2 MHz

UL Japan, Inc.

Ise EMC Lab.

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test specification : FCC Part 15 Subpart B: 2015, final revised on November 23, 2015
*Some parts are effective on and after December 17, 2015 or December 23, 2015.
The revision does not affect the test specification applied to the EUT.

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

*The tests were performed based on the Test plan from Sharp Corporation (Issued No.: EAS-S7229 Ver1.0).

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2009 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 4.5 dB 0.16760 MHz, L [AV] 6.0 dB 2.30950 MHz, L	Complied
Radiated emission	ANSI C63.4: 2009 8. Radiated emission measurements	Class B	N/A	9.2 dB 72.024 MHz, Horizontal, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

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3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k = 2$.

Frequency range	Conducted emission using AMN(LISN) (+dB)
0.009 – 0.15MHz	3.5 dB
0.15 – 30MHz	2.9 dB

Polarity	Radiated emission (Below 1GHz)			
	(3 m*)(+dB)		(10 m*)(+dB)	
	30 – 300 MHz	300 – 1000MHz	30 – 300 MHz	300 – 1000MHz
Horizontal	4.8 dB	5.2 dB	4.8 dB	5.0 dB
Vertical	4.5 dB	5.9 dB	4.8 dB	5.1 dB

Radiated emission				
(3 m*)(+dB)		(1 m*)(+dB)	(0.5 m*)(+dB)	(10 m*)(+dB)
1 – 6GHz	6 – 18GHz	10 – 26.5 GHz	26.5 – 40GHz	1 -18 GHz
5.1 dB	5.3 dB	5.1 dB	5.1 dB	5.3 dB

* Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3 m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0
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Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.8 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

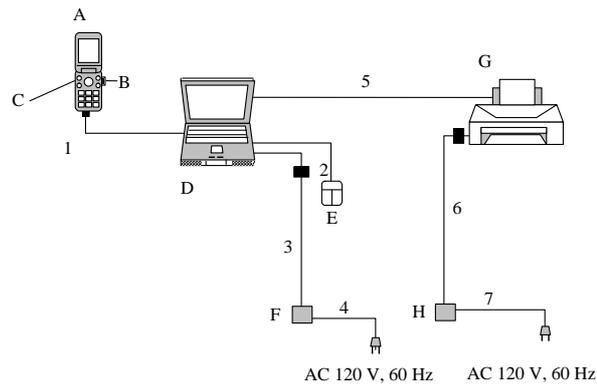
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



■ : Ferrite core which has been standard on support equipment.

*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	SH-03H	004401/11/568049/4	Sharp Corporation	EUT
B	microSD Memory Card	SD-C02G	None	TOSHIBA	-
C	Lithium-Ion Battery	SH43	YEA	Sharp Corporation	EUT
D	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	Dell	-
E	Mouse	M-UAG120	LZ733B70EVV	TOSHIBA	-
F	AC Adapter(PC)	PA-1650-05D3	CN-0YD637-71615-64Q-2243	Dell	-
G	Printer	895Cxi	SG8BA1W18J	Hewlett Packard	-
H	AC Adapter(Printer)	C4557-60004	C8L01B	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	1.2	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adaptor Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	0.85	Unshielded	Unshielded	-
5	Parallel Cable	1.85	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place : No.1 semi anechoic chamber
Temperature : See data
Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The rear of tabletop was located 40 cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80 cm from any other grounded conducting surface. EUT was located 80 cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30 cm to 40 cm long and were hanged at a 40 cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment.

Photographs of the set up are shown in Appendix 3.

Frequency range : 0.15 MHz - 30 MHz
EUT position : Table top
EUT operation mode : See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and CISPR AV
IF Bandwidth : 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: January 7, 2016

Test engineer: Takumi Shimada

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SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No.1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The EUT was set on the center the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30 MHz - 300 MHz (Biconical antenna) / 300 MHz - 1000 MHz (Logperiodic antenna)
: 1000 MHz - 6000 MHz (Horn antenna)
Test distance : 3 m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver.

The radiated emission measurements were made with the following detector function of the Test Receiver.

Frequency	Below 1 GHz	Above 1 GHz
Instrument used	Test Receiver	Test Receiver
IF Bandwidth	QP: BW 120 kHz	PK: BW 1 MHz, CISPR AV: BW 1 MHz

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: January 7, 2016

Test engineer: Takumi Shimada

UL Japan, Inc.

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APPENDIX 1: Test date

Conducted Emission

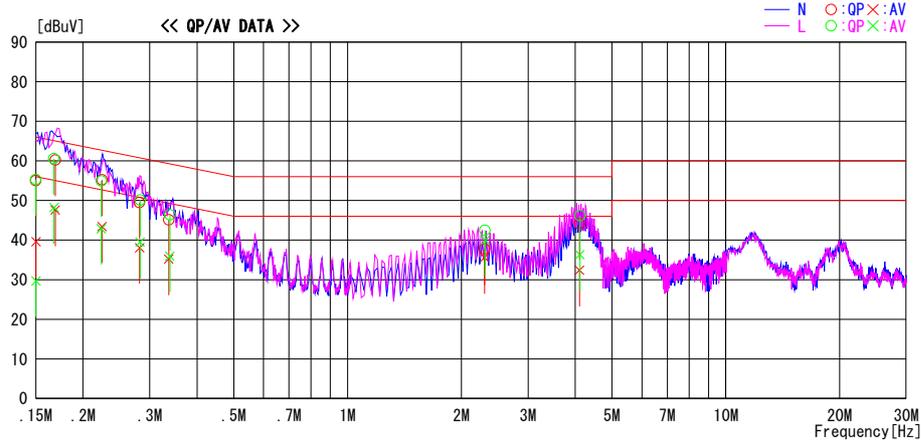
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/01/07

Report No. : 11075975H
Temp./Humi. : 20deg.C / 32% RH
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	42.1	16.5	13.2	55.3	29.7	66.0	56.0	10.7	26.3	L	
0.15000	41.8	26.4	13.2	55.0	39.6	66.0	56.0	11.0	16.4	N	
0.16891	47.0	34.4	13.2	60.2	47.6	65.0	55.0	4.8	7.4	N	
0.16760	47.4	35.0	13.2	60.6	48.2	65.1	55.1	4.5	6.9	L	
0.22350	41.6	29.6	13.3	54.9	42.9	62.7	52.7	7.8	9.8	L	
0.22440	41.9	30.1	13.3	55.2	43.4	62.7	52.7	7.5	9.3	N	
0.28200	36.2	24.8	13.3	49.5	38.1	60.8	50.8	11.3	12.7	N	
0.28300	36.8	26.2	13.3	50.1	39.5	60.7	50.7	10.6	11.2	L	
0.33900	33.1	22.7	13.3	46.4	36.0	59.2	49.2	12.8	13.2	L	
0.33680	31.8	21.9	13.3	45.1	35.2	59.3	49.3	14.2	14.1	N	
2.30950	28.9	26.4	13.6	42.5	40.0	56.0	46.0	13.5	6.0	L	
4.11240	32.3	22.4	13.9	46.2	36.3	56.0	46.0	9.8	9.7	L	
2.30360	24.1	22.0	13.6	37.7	35.6	56.0	46.0	18.3	10.4	N	
4.10400	30.2	18.5	13.9	44.1	32.4	56.0	46.0	11.9	13.6	N	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C.F (LISN + ATTEN + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

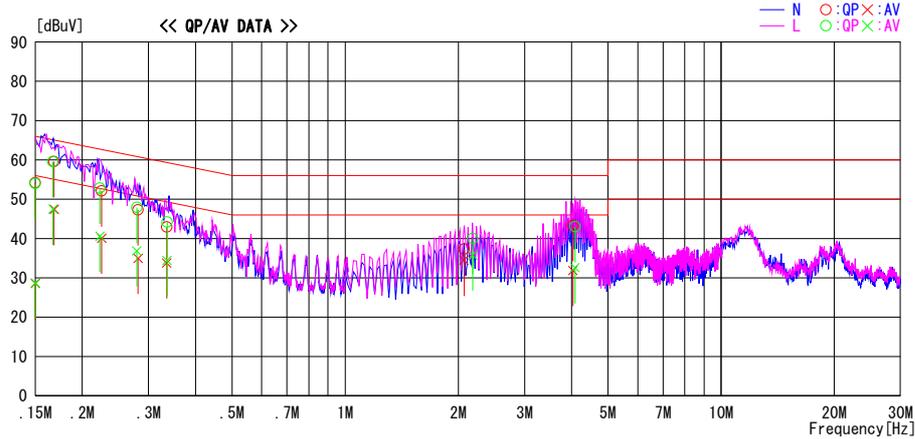
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/01/07

Report No. : 11075975H

Temp./Humi. : 20deg. C. / 32% RH
Engineer : Takumi Shimada

Mode / Remarks : Standby Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	40.8	15.5	13.2	54.0	28.7	66.0	56.0	12.0	27.3	L	
0.15000	41.0	15.4	13.2	54.2	28.6	66.0	56.0	11.8	27.4	N	
0.16832	46.4	34.2	13.2	59.6	47.4	65.0	55.0	5.4	7.6	N	
0.16710	46.4	34.3	13.2	59.6	47.5	65.1	55.1	5.5	7.6	L	
0.22510	38.8	26.8	13.3	52.1	40.1	62.6	52.6	10.5	12.5	N	
0.22282	39.5	27.3	13.3	52.8	40.6	62.7	52.7	9.9	12.1	L	
0.28140	34.0	21.7	13.3	47.3	35.0	60.8	50.8	13.5	15.8	N	
0.27924	34.6	23.6	13.3	47.9	36.9	60.8	50.8	12.9	13.9	L	
0.33612	30.9	21.1	13.3	44.2	34.4	59.3	49.3	15.1	14.9	L	
0.33540	29.6	20.5	13.3	42.9	33.8	59.3	49.3	16.4	15.5	N	
2.07130	23.8	21.0	13.5	37.3	34.5	56.0	46.0	18.7	11.5	N	
2.18470	26.4	22.2	13.6	40.0	35.8	56.0	46.0	16.0	10.2	L	
4.08480	29.2	18.8	13.8	43.0	32.6	56.0	46.0	13.0	13.4	L	
4.03200	29.6	18.1	13.8	43.4	31.9	56.0	46.0	12.6	14.1	N	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C. F (LISN + ATTEN + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Below 1GHz)

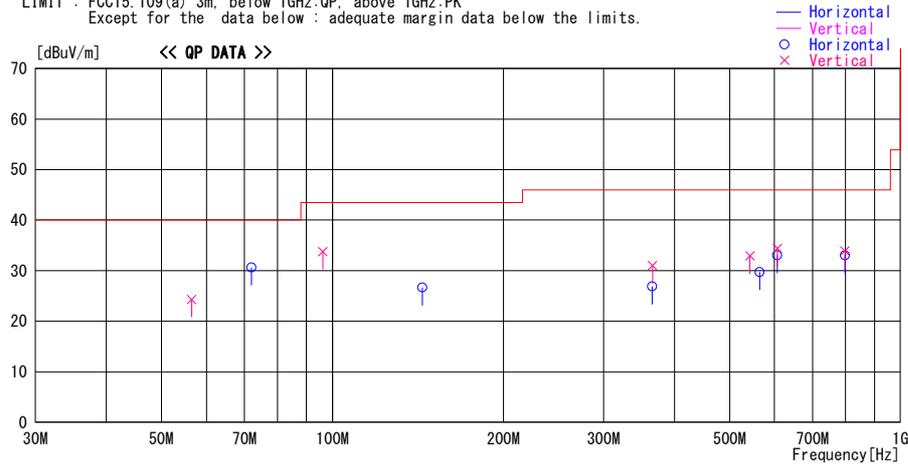
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/01/07

Report No. : 11075975H
Temp./Humi. : 20deg.C / 32% RH
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode Worst-Axis (Hori X Vert X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Loss& Gain [dB]							
56.513	46.8	QP	8.5	-31.0	24.3	170	100	Vert.	40.0	15.7	
72.024	55.2	QP	6.2	-30.8	30.6	102	228	Hori.	40.0	9.4	
143.997	42.0	QP	14.5	-29.8	26.7	267	238	Hori.	43.5	16.8	
96.134	54.8	QP	9.4	-30.4	33.8	187	100	Vert.	43.5	9.7	
365.829	42.1	QP	16.6	-27.7	31.0	202	153	Vert.	46.0	15.0	
365.732	38.1	QP	16.5	-27.7	26.9	167	100	Hori.	46.0	19.1	
564.674	36.4	QP	19.0	-25.7	29.7	225	173	Hori.	46.0	16.3	
543.226	40.0	QP	18.7	-25.8	32.9	359	100	Vert.	46.0	13.1	
607.127	40.3	QP	19.5	-25.4	34.4	8	100	Vert.	46.0	11.6	
607.134	38.9	QP	19.5	-25.4	33.0	316	146	Hori.	46.0	13.0	
797.960	36.2	QP	22.0	-24.3	33.9	61	155	Vert.	46.0	12.1	
798.284	35.3	QP	22.0	-24.3	33.0	359	112	Hori.	46.0	13.0	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE + / (CABLE) + ATTEN - GAIN (AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Below 1GHz)

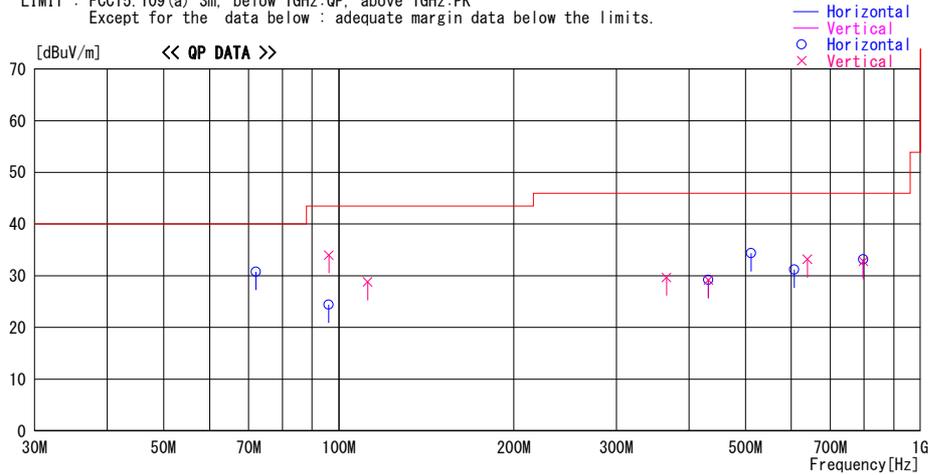
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/01/07

Report No. : 11075975H
Temp./Humi. : 20deg. C. / 32% RH
Engineer : Takumi Shimada

Mode / Remarks : Standby Mode Worst-Axis (Hori X Vert X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Loss& Gain [dB]							
72.024	55.4	QP	6.2	-30.8	30.8	110	281	Hori.	40.0	9.2	
96.031	45.5	QP	9.3	-30.4	24.4	113	178	Hori.	43.5	19.1	
96.134	55.0	QP	9.4	-30.4	34.0	158	100	Vert.	43.5	9.5	
112.127	47.3	QP	11.7	-30.2	28.8	175	100	Vert.	43.5	14.7	
365.792	40.8	QP	16.6	-27.7	29.7	154	163	Vert.	46.0	16.3	
431.990	38.4	QP	17.8	-27.0	29.2	359	136	Vert.	46.0	16.8	
431.990	38.4	QP	17.8	-27.0	29.2	355	100	Hori.	46.0	16.8	
511.271	42.3	QP	18.2	-26.1	34.4	160	125	Hori.	46.0	11.6	
607.134	37.1	QP	19.5	-25.4	31.2	121	125	Hori.	46.0	14.8	
639.089	38.7	QP	19.8	-25.3	33.2	191	160	Vert.	46.0	12.8	
797.840	35.5	QP	22.0	-24.3	33.2	359	200	Hori.	46.0	12.8	
797.840	35.1	QP	22.0	-24.3	32.8	41	100	Vert.	46.0	13.2	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE + ATT - GAIN(AMP))

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)

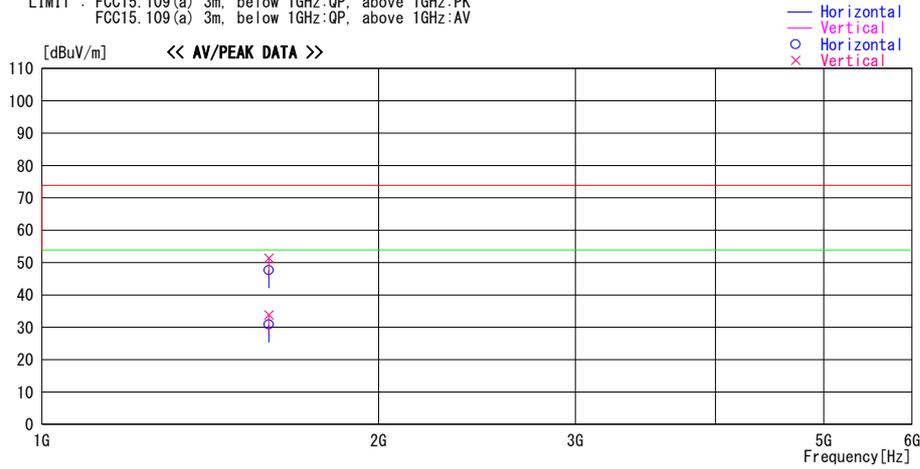
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/01/07

Report No. : 11075975H
Temp./Humi. : 20deg. C. / 32% RH
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode Worst-Axis (Hori X Vert X)

LIMIT : FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1595.800	59.9	PK	25.6	-34.1	51.4	359	400	Vert.	73.9	22.5	
1595.800	42.3	AV	25.6	-34.1	33.8	359	400	Vert.	53.9	20.1	
1595.800	56.2	PK	25.6	-34.1	47.7	42	372	Hori.	73.9	26.2	
1595.800	39.4	AV	25.6	-34.1	30.9	42	372	Hori.	53.9	23.0	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz--:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE + ATT - GAIN(AMP))

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)

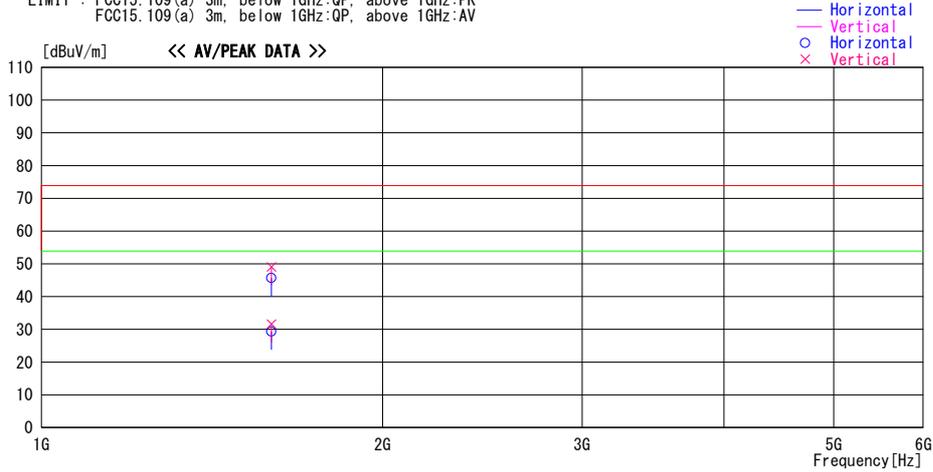
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/01/07

Report No. : 11075975H
Temp./Humi. : 20deg. C. / 32% RH
Engineer : Takumi Shimada

Mode / Remarks : Standby Mode Worst-Axis (Hori X Vert X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]							
1995.800	57.6	PK	25.6	-34.1	49.1	359	373	Vert.	73.9	24.8	
1995.800	40.1	AV	25.6	-34.1	31.6	359	373	Vert.	53.9	22.3	
1995.800	54.2	PK	25.6	-34.1	45.7	54	351	Hori.	73.9	28.2	
1995.800	37.9	AV	25.6	-34.1	29.4	54	351	Hori.	53.9	24.5	

CHART:WITH FACTOR ANT TYPE: <30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE + ATT - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2015/09/19 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2015/01/13 * 12
MJM-25	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Receiver	Rohde & Schwarz	ESU26	100412	RE/CE	2015/06/08 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2015/11/02 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2015/11/03 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2015/11/10 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/TSJ	-	-	RE	2015/09/29 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2015/02/03 * 12
MMM-03	Digital Tester	Fluke	FLUKE 26-3	78030621	RE/CE	2015/08/19 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2015/05/18 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2015/02/04 * 12
MCC-165	Microwave Cable	Junkosha	MWX221	1203S213(1m) / 1311S166(5m)	RE	2015/11/10 * 12
MLS-23	LISN(AMN)	Schwarzbeck	NSLK8127	8127-729	CE(EUT)	2015/07/10 * 12
MLS-26	LISN(AMN)	Schwarzbeck	NSLK8127	8127-732	CE(AE)	2015/07/17 * 12
MTA-30	Terminator	TME	CT-01	-	CE	2015/01/19 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/3D-2W(7.5m)/RG400u(1.5m)/RFM-E421(Switcher)	- /01068(Switcher)	CE	2015/09/29 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2015/01/29 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emissions

RE: Radiated Emissions

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